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	L8	('6744274' '6681354')!.ABPN1,NRPN,PN,TBAN,WKU.	4
	DB=	USPT,PGPB,JPAB,EPAB,DWPI,TDBD; PLUR=YES; OP=ADJ	
	L7	(('5878051') [ABPN1,NRPN,PN,TBAN,WKU]) and @pd > 20040113	0
.	L6	(L5 and (test\$3 or inspect\$4 or check\$4 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4 or stimul\$7) near2 (self\$3 or built\$4) same (pld or spld or cpld or fpga or programmable near2 (logic or device)) same configur\$7 same (rom or prom or eeprom or read\$1only near memory)) and @pd > 20040113	2
	L5	((test\$3 or inspect\$4 or check\$4 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4 or stimul\$7) near2 (self\$3 or built\$4) same (pld or spld or cpld or fpga or programmable near2 (logic or device)) same configur\$7) and @pd > 20040113	16
	DB=1	PGPB, USPT, USOC, EPAB, JPAB, DWPI, TDBD; PLUR=YES; OP=OR	
	L4	('6574761')!.PN.	2
	L3	(fpga with (self\$1 or built\$4) near2 test\$3 same logic\$4 and fpga with (self\$1 or built\$4) near2 test\$3)	40
	L2	(fpga with (self\$1 or built\$4) near2 test\$3)	75
	L1	(fpga with (self\$1 or built\$4) near2 test\$3 same logic\$4 and format and fpga with (self\$1 or built\$4) near2 test\$3 same logic\$4 and fpga with (self\$1 or built\$4) near2 test\$3)	6

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